Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,126	LAI, JEN-SHOW	
Examiner	Art Unit	
David Buttner	1712	

SEARCHED					
Class	Subclass	Date	Examiner		
_		- <u> </u>			
		·-·			
m.,:					
		,,,,,			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	L				

	CH STRATEGY	)
	DATE	EXMR
chem ab	6/22/2006	DB
west	6/22/2006	DB
·		
······································		